

Test Report

Report No.: SZPR101229117701E

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Client : Samtec Electronics (HuiZhou) Limited

Address : Huangxi Industrial Park, Shiwan Town, Boluo County, Huizhou City, Guangdong Province, China

Report on the submitted sample said to be:

Sample Name : SIR1-15-L-S-A

Sample Description : Normal

Amount of Sample : 11 pcs

Sample Received Date : Dec. 31, 2010

Sample tested Date : Jan. 07, 2011~ Jan. 13, 2011

Test Requested: (Please see page 2.)

Group	Test Sequence	Test Item
Seq. (c) (001~008)	1	Low Level Contact Resistance (LLCR)
	2	Mechanical Shock Test
	3	Low Level Contact Resistance (LLCR)
	4	Random Vibration Test
	5	Low Level Contact Resistance (LLCR)
Seq. (d) (009~011)	1	Mechanical Shock Test
	2	Random Vibration Test

Test Results: Please see the attached sheets.

Inspected by: Tim Sun
Engineer

Approved by: Roger Diao
Lab Supervisor

Approved date: Mar 02, 2011



Building C, Hongwei Industrial Zone, Baoan 70 District, Shenzhen

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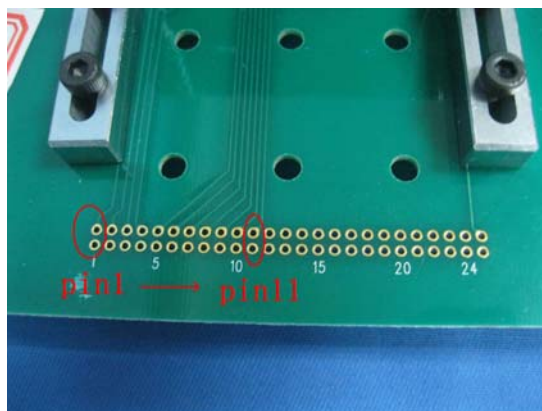
Data Summary:

Group	Test Sequence	Test Item	Requirement	Result
Seq. (c) (001~008)	1	Low Level Contact Resistance (LLCR)	$\Delta R \leq 10 \text{ m}\Omega$ No damage	Pass
	2	Mechanical Shock Test		
	3	Low Level Contact Resistance (LLCR)		
	4	Random Vibration Test	$\Delta R \leq 10 \text{ m}\Omega$ No damage	Pass
	5	Low Level Contact Resistance (LLCR)		
Seq. (d) (009~011)	1	Mechanical Shock Test	No damage	Pass
			0.1 microsecond	Pass
	2	Random Vibration Test	No damage	Pass
			1 microsecond	Pass

Tested Samples:

Test Seq.	Sample No.	Sample Name	Quantity
Seq. (c)	001~008	SIR1-15-L-S-A	8 pcs
Seq. (d)	009~011	SIR1-15-L-S-A	3 pcs

Pin No. of Sample:



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Sample Photos before the Test:



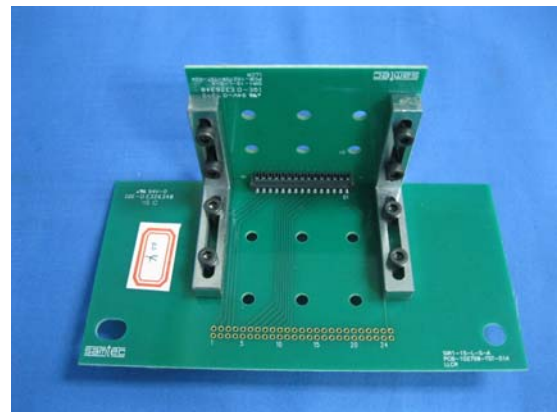
001



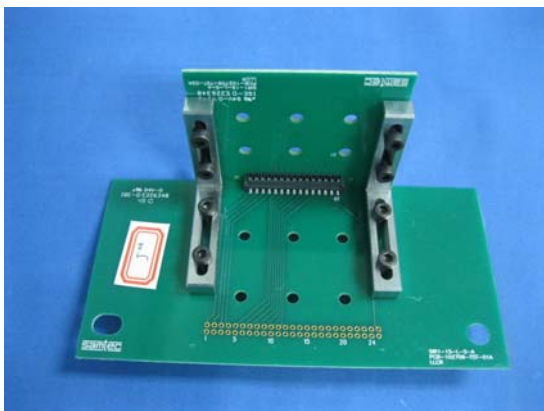
002



003



004



005



006

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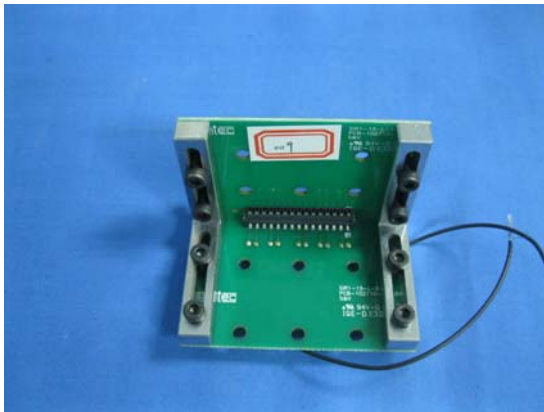
Sample Photos before the Test:



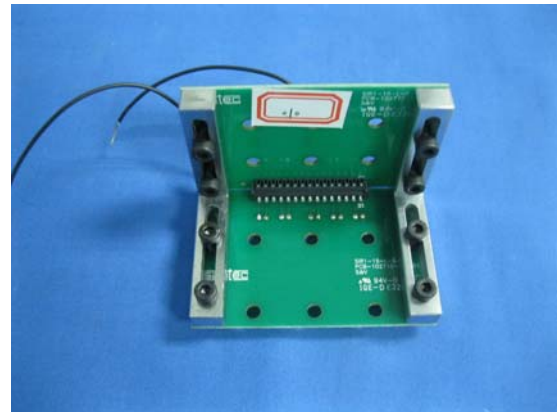
007



008



009



010



011

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Test Seq. (c)

Test Item 1: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 21℃ Humidity: 51%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Samples: PR101229117701-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

---Test Current: 10 milliamps max

---Measure and record the Low Level Contact Resistance

Test Results: Please see the appendixes from page 37 to page 40.

Test Photo:



LLCR test



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Test Seq. (c)

Test Item 2: Mechanical Shock Test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May 24, 2011

(2) Environmental Conditions:

Temperature: 21°C Humidity: 51%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

- Wave form: Half-sine
- Acceleration: 100 g_n
- Pulse duration: 6 ms
- Direction: Axis $\pm X$, $\pm Y$, $\pm Z$
- Number of shocks: 3 shocks /axis, 18 shocks in total

(6) Acceptance criteria:

- There shall be no evidence of physical damage to the tested samples.

(7) Remark:

- Samples 001~004 and 005~008 were tested separately

Test Results: There was no evidence of physical damage to the tested samples after the test.

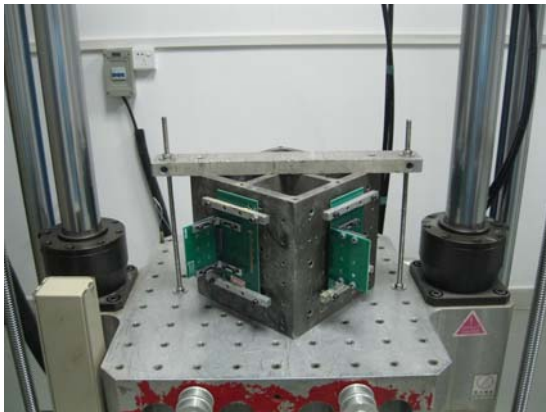


Test Report

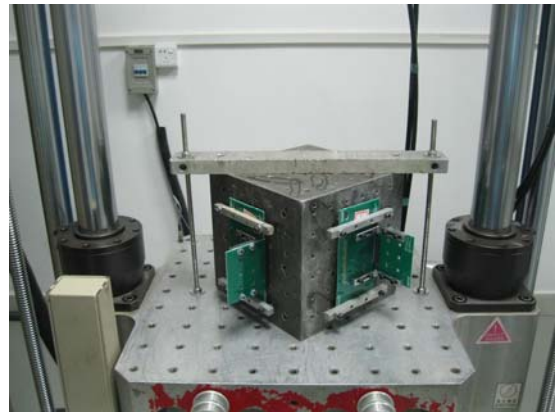
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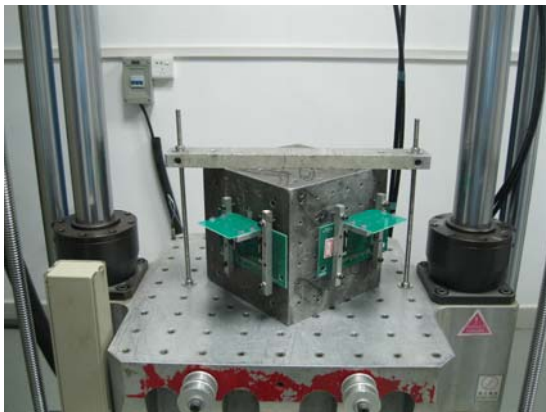
Test Photos:



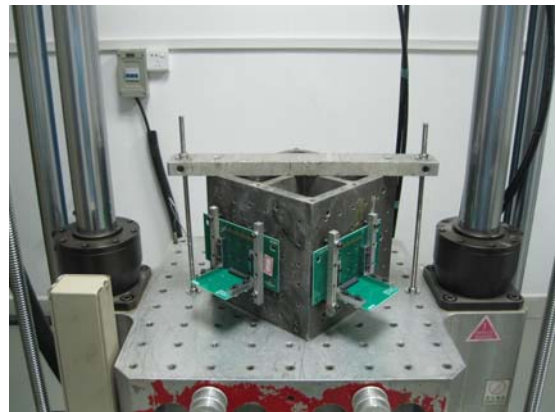
Axis +X



Axis -X



Axis +Y



Axis -Y



Axis +Z



Axis -Z



Test Report

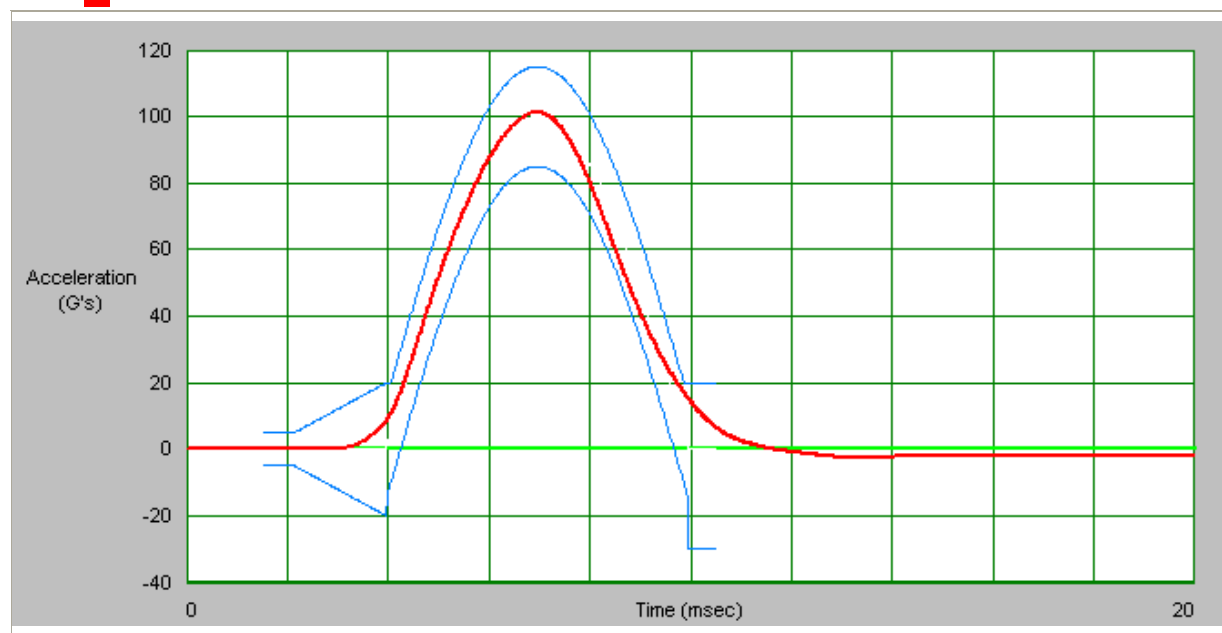
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.15	6.24	149.75	407.17	101.15	-2.60



Axis +X





Test Report

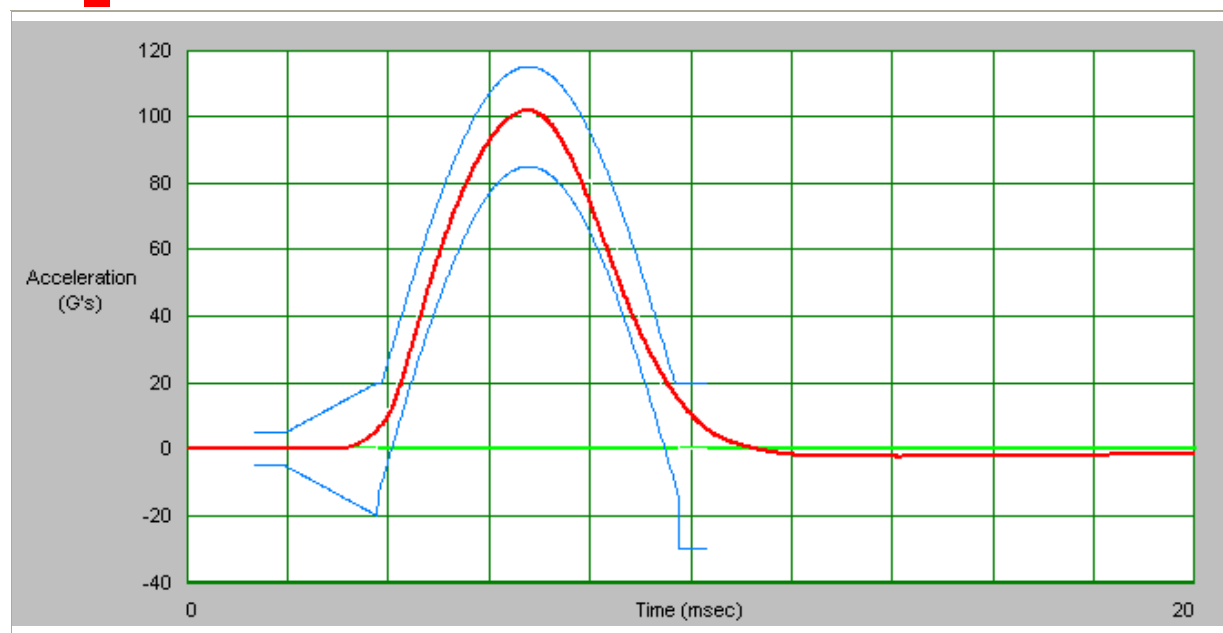
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.70	6.04	147.85	425.17	101.70	-2.32



Axis -X





Test Report

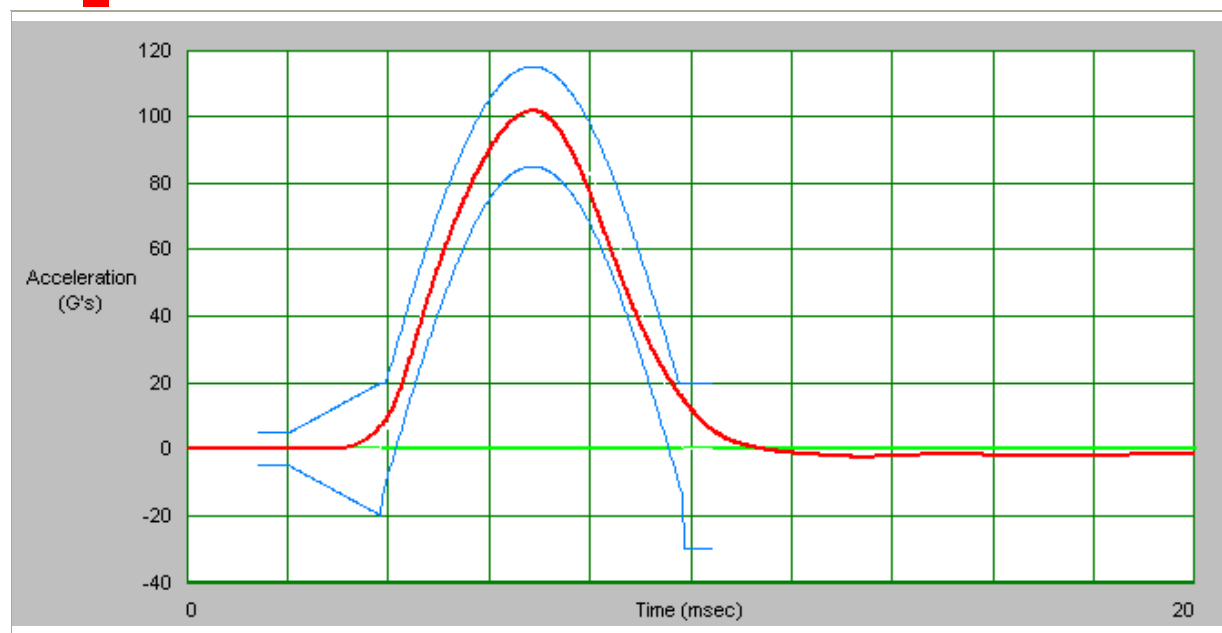
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.67	6.12	148.56	420.88	101.67	-2.38



Axis +Y





Test Report

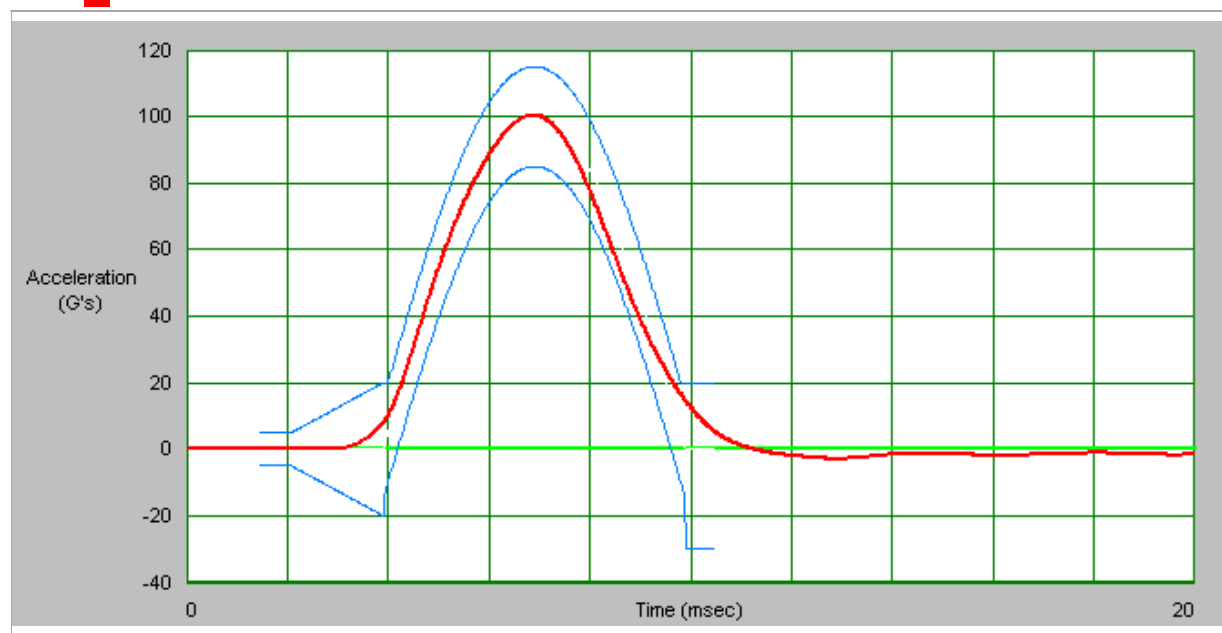
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	100.33	6.18	148.43	415.28	100.33	-2.95



Axis -Y





Test Report

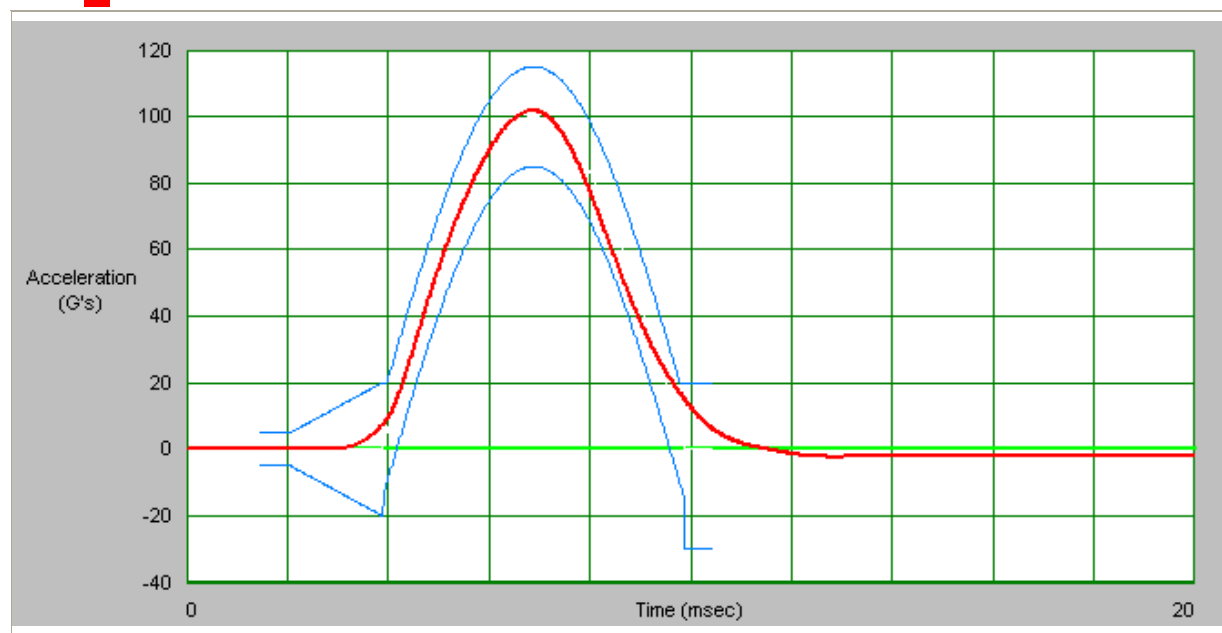
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.77	6.14	148.98	420.88	101.77	-2.35



Axis +Z





Test Report

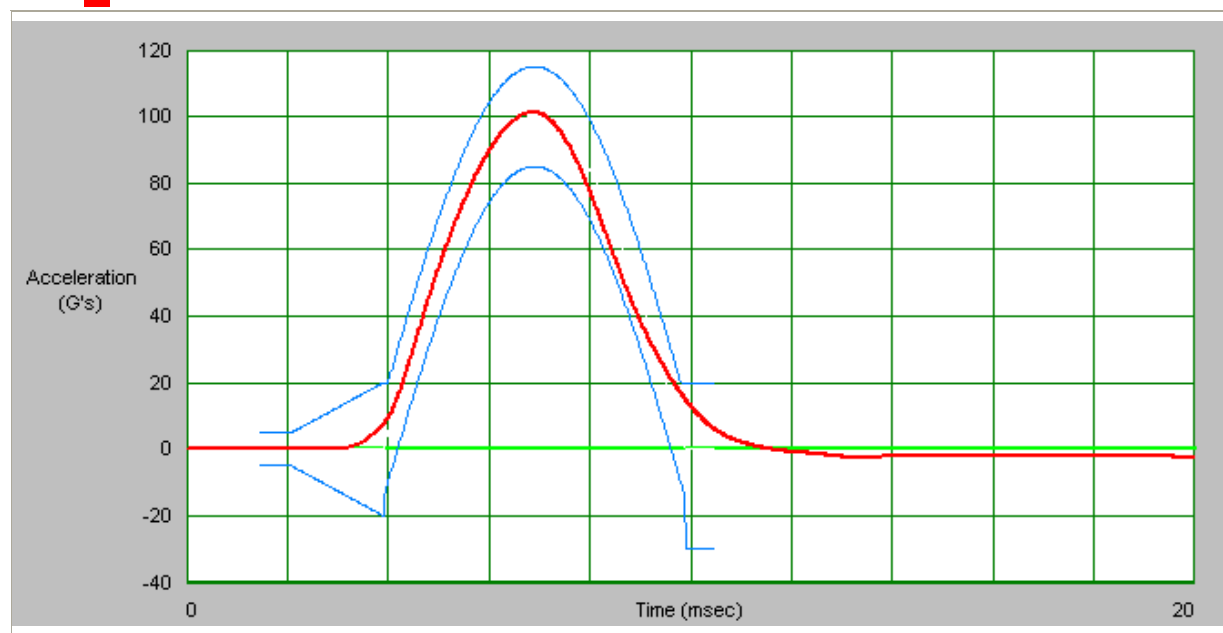
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.26	6.16	149.02	420.88	101.26	-2.53



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Test Seq. (c)

Test Item 3: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 21°C

Humidity: 51%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

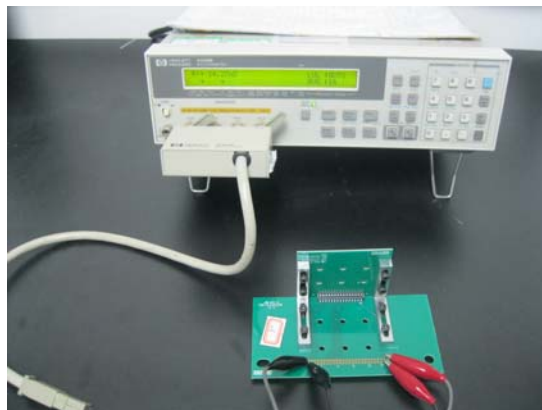
---Test Current: 10 milliamps max

--- Measure and record the Low Level Contact Resistance

--- $\Delta R \leq 10 \text{ m}\Omega$

Test Results: Please see the appendixes from page 37 to page 40.

Test Photo:



LLCR test



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Test Seq. (c):

Test Item 4: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ20020	Mar. 18, 2011

(2) Environmental Conditions:

Temperature: 18°C Humidity: 47%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: PR101229117701-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency (Hz)	PSD (g^2/Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56 Grms

---Direction: Axis X, Y, Z

---Test duration: 2hours/axis

(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

Test Results: There was no evidence of physical damage to the tested samples after the test.

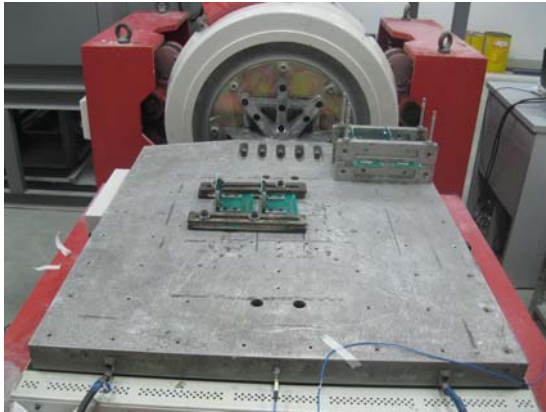


Test Report

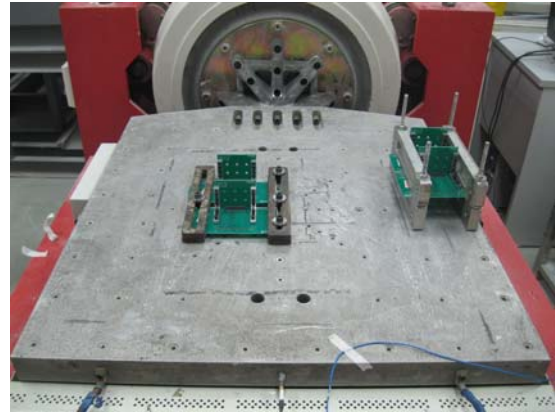
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Test Photos:



Axis X



Axis Y



Axis Z

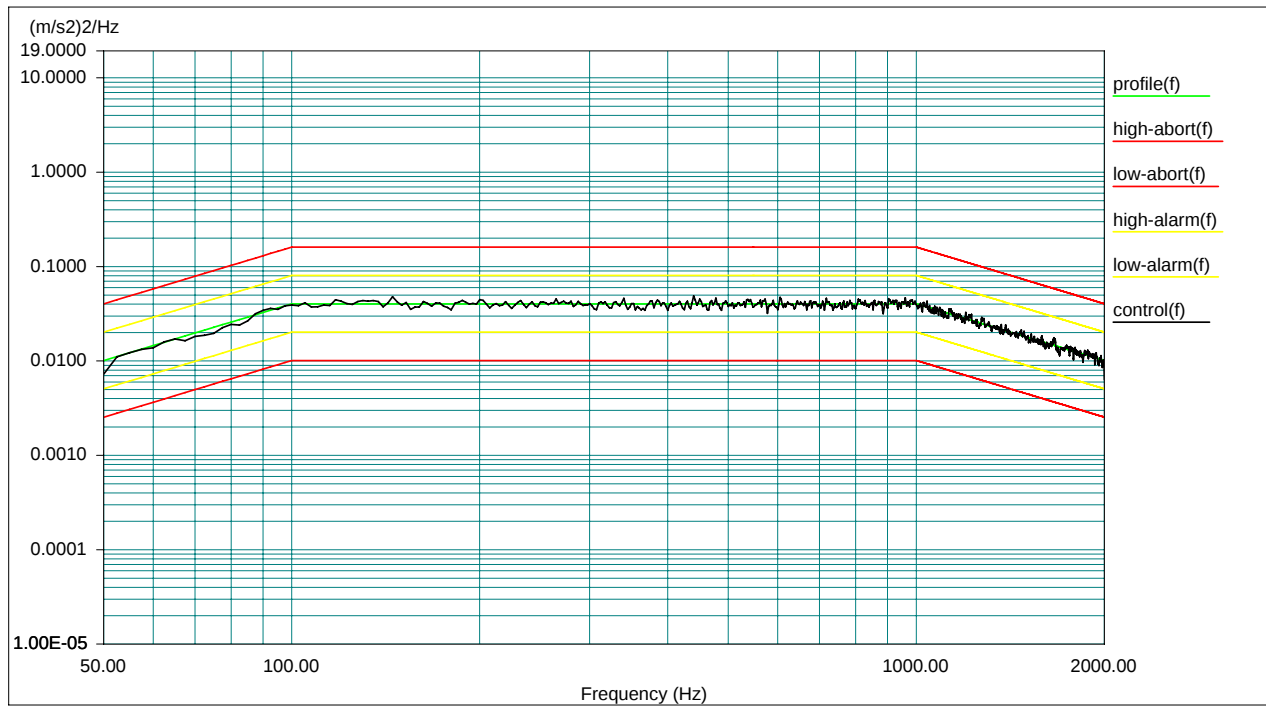


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Test Curve:



Level: 100 %

Control RMS: 7.541538 m/s² Full Level Elapsed Time: 02:00:00

Lines: 800 Frame Time: 0.400000

Seconds

Demand RMS: 7.564621 m/s² Remaining Time:

00:00:00

DOF: 154

dF: 2.500000 Hz

Data saved at 02:58:38 AM, Thursday, January 13, 2011

Report created at 02:58:39 AM, Thursday, January 13, 2011

Axis X



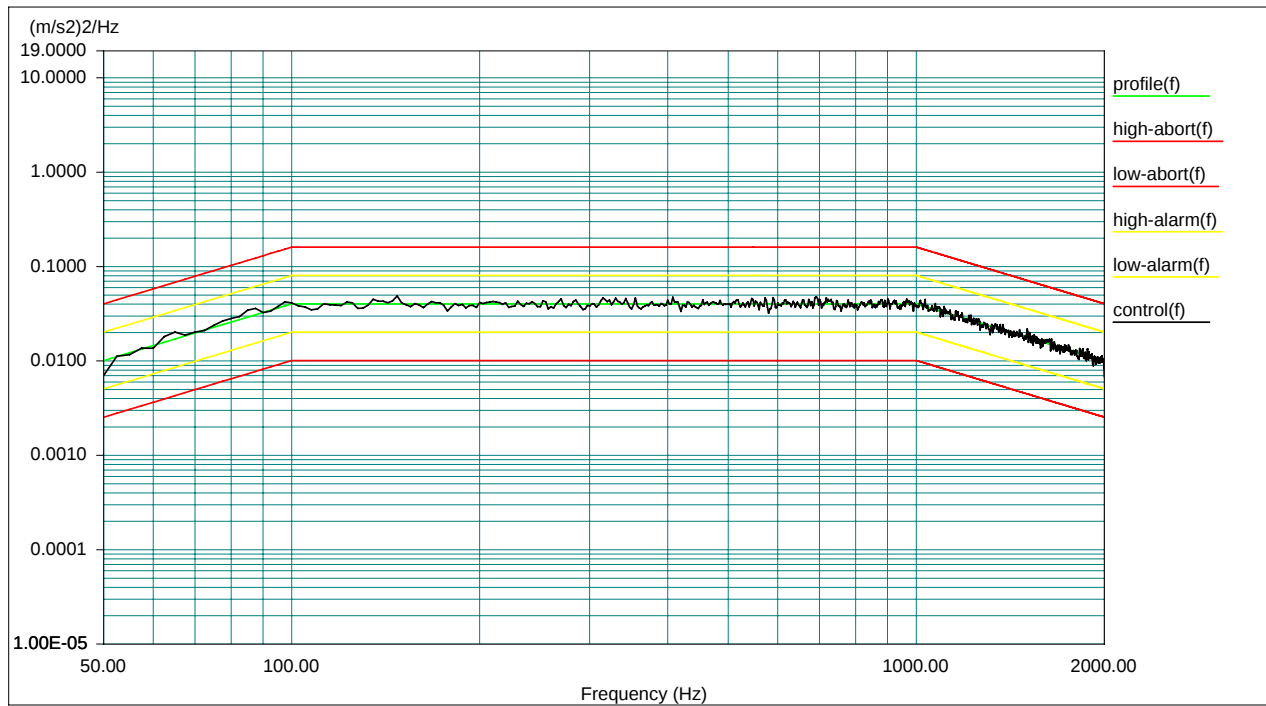


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Test Curve:



Level: 100 %

Control RMS: 7.555688 m/s² Full Level Elapsed Time: 02:00:00 Lines: 800 Frame Time: 0.400000
Seconds

Demand RMS: 7.564621 m/s² Remaining Time: 00:00:00 DOF: 154 dF: 2.500000 Hz

Data saved at 09:50:41 PM, Wednesday, January 12, 2011

Report created at 09:50:41 PM, Wednesday, January 12, 2011

Axis Y



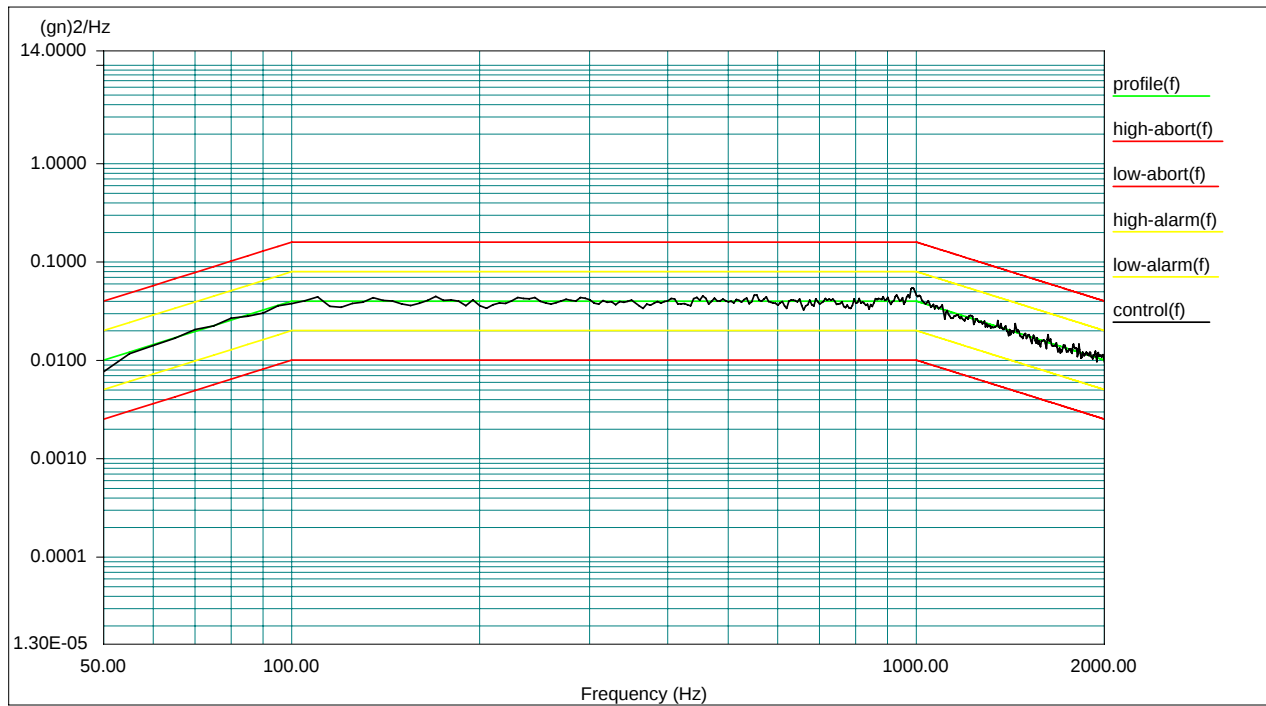


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Test Curve:



Level: 100 %

Control RMS: 7.970019 m/s² Full Level Elapsed Time: 02:00:00

Lines: 800 Frame Time: 0.400000

Seconds

Demand RMS: 7.564621 m/s² Remaining Time: 00:00:00

DOF: 154 dF: 2.500000 Hz

Data saved at 08:37:48 AM, Wednesday, January 12, 2011

Report created at 08:37:49 AM, Wednesday, January 12, 2011

Axis Z

Test Report

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Test Seq. (c):

Test Item 5: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 18°C

Humidity: 47%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Sample: PR101229117701-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

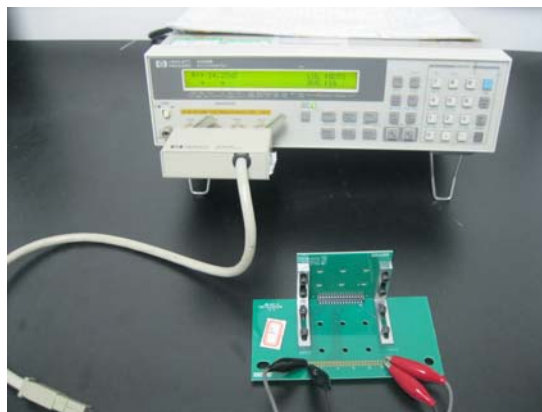
---Test Current: 10 milliamps max

---Measure and record the Low Level Contact Resistance

--- $\Delta R \leq 10 \text{ m}\Omega$

Test Results: Please see the appendixes from page 37 to page 40.

Test Photo:



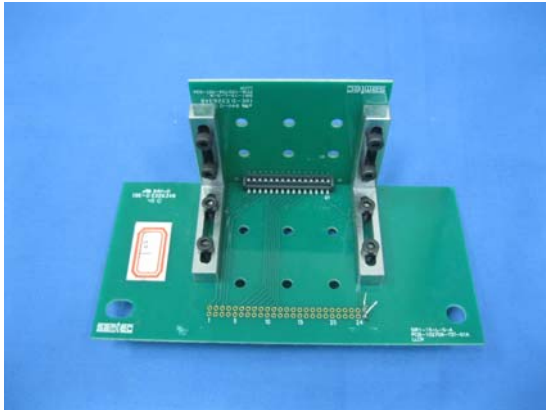
LLCR test

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Sample Photos after testing Seq. (c):



001



002



003



004



005



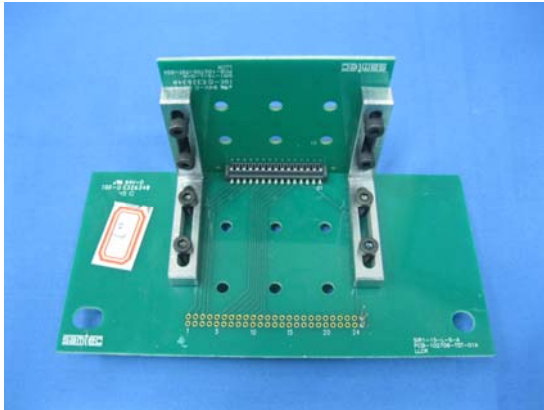
006

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Sample Photos after testing Seq. (c):



007



008



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Test Seq. (d)

Test Item 1: Mechanical Shock Test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May 24, 2011
Instantaneous circuit tester	NM11A	BTTEELSZ20016	Oct. 13, 2011

(2) Environmental Conditions:

Temperature: 21℃ Humidity: 51%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Samples: PR101229117701-(009~011)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

- Wave form: Half-sine
- Acceleration: 100 g_n
- Pulse duration: 6 ms
- Direction: Axis ±X, ±Y, ±Z
- Number of shocks: 3 shocks /axis, 18 times in total
- Monitor the discontinuity duration of samples during the test

(6) Acceptance criteria:

- There shall be no evidence of physical damage to the tested samples.
- There shall be no low microsecond event detected greater than 0.1 microsecond.

Test Results: After the test, there was no evidence of physical damage to the tested samples and the low microsecond event detected was never greater than 0.1 microsecond. Other characteristics should be evaluated by the client.

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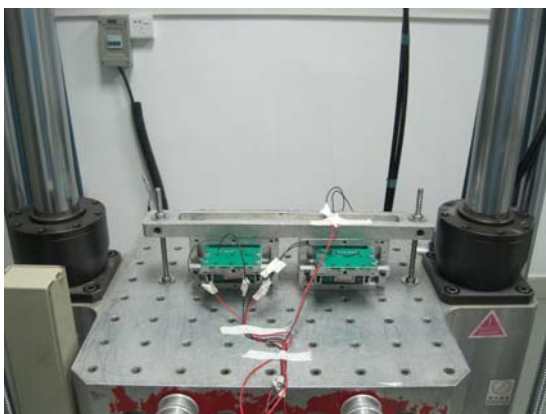
Test Photos:



Axis +X



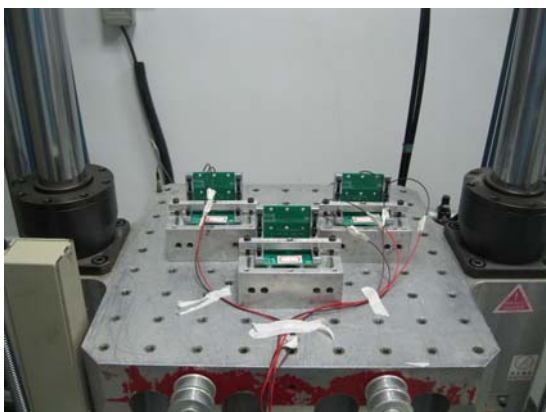
Axis -X



Axis +Y



Axis -Y



Axis +Z



Axis -Z

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Test Photo:

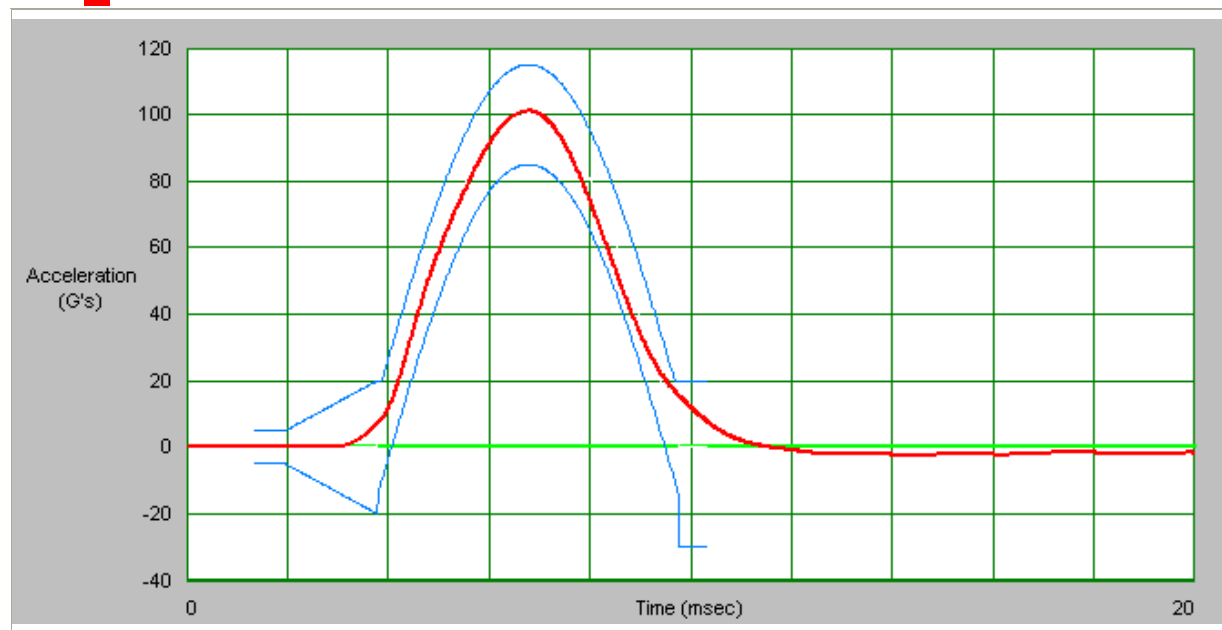


Monitor during the test

Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.00	6.22	148.58	504.03	101.00	-2.67



Axis +X



Test Report

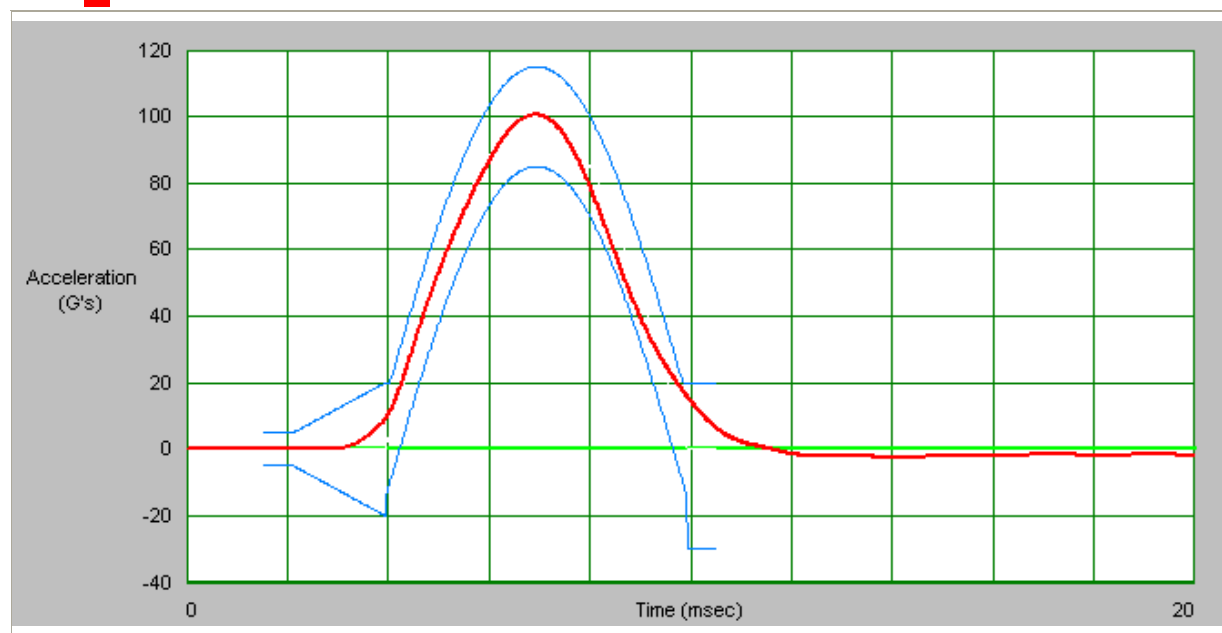
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	100.44	6.28	149.30	449.64	100.44	-2.66



Axis -X





Test Report

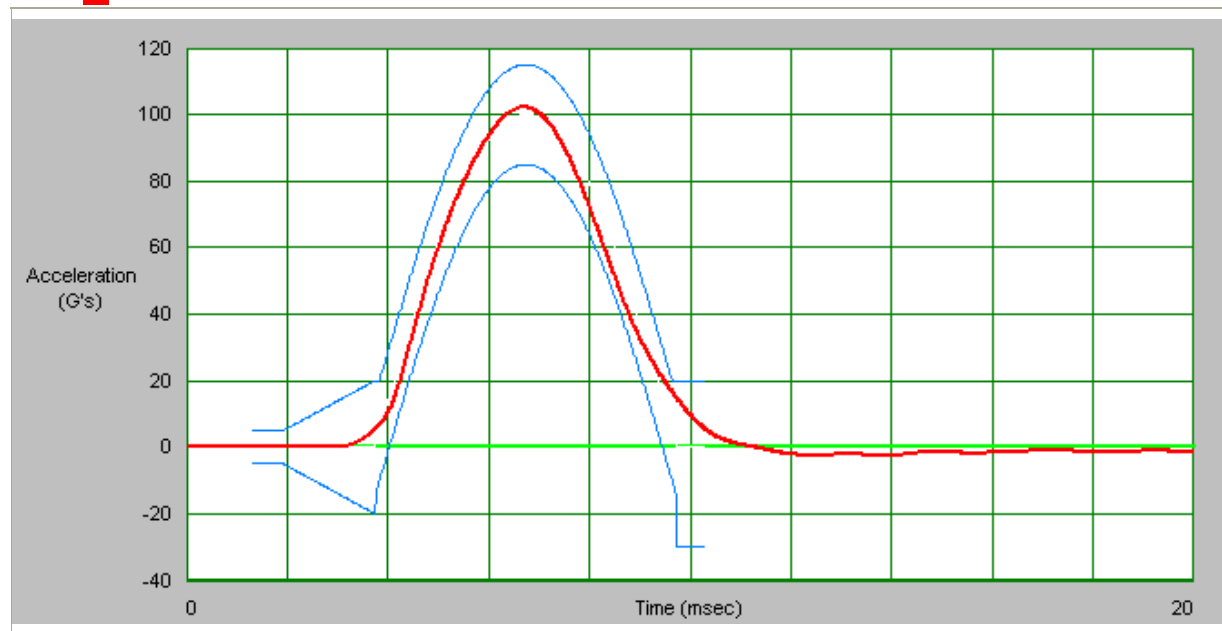
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	102.20	6.02	147.17	477.10	102.20	-2.70



Axis +Y





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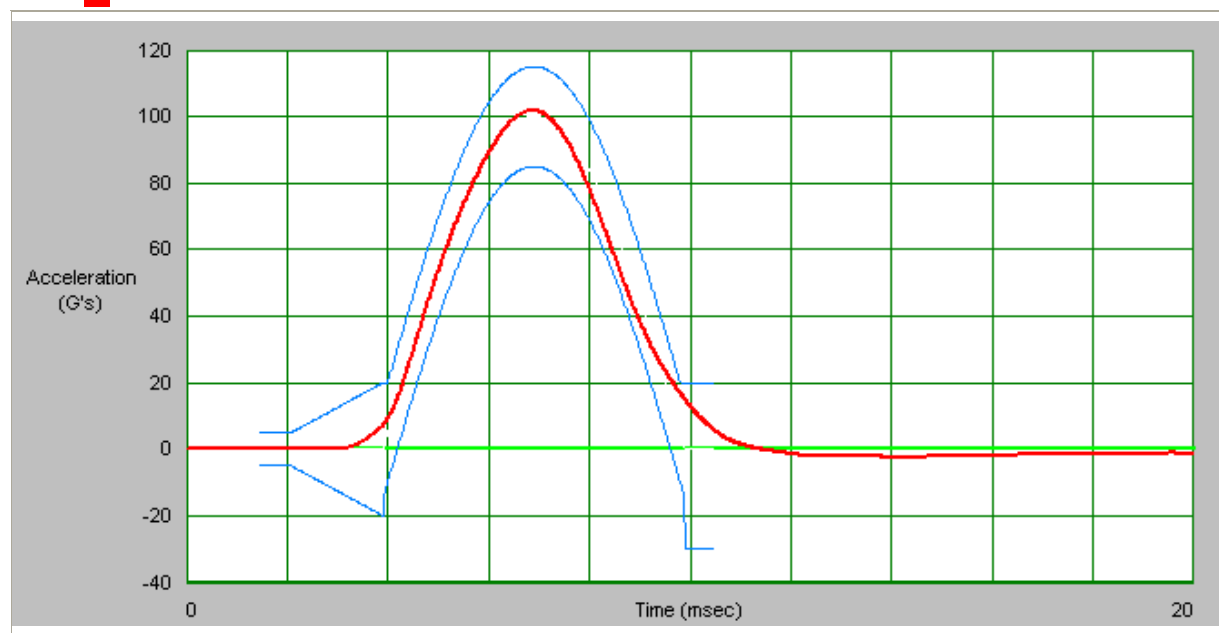
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	101.76	6.16	148.71	423.73	101.76	-2.70



Axis -Y





Test Report

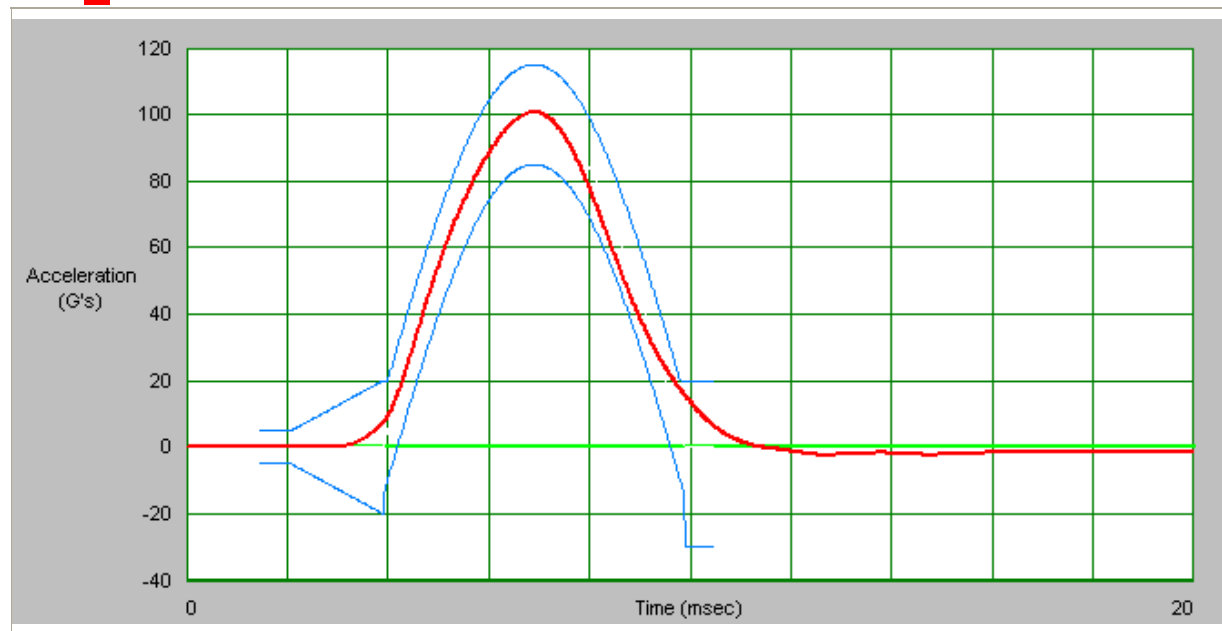
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	100.65	6.20	148.80	449.64	100.65	-2.42



Axis +Z





Test Report

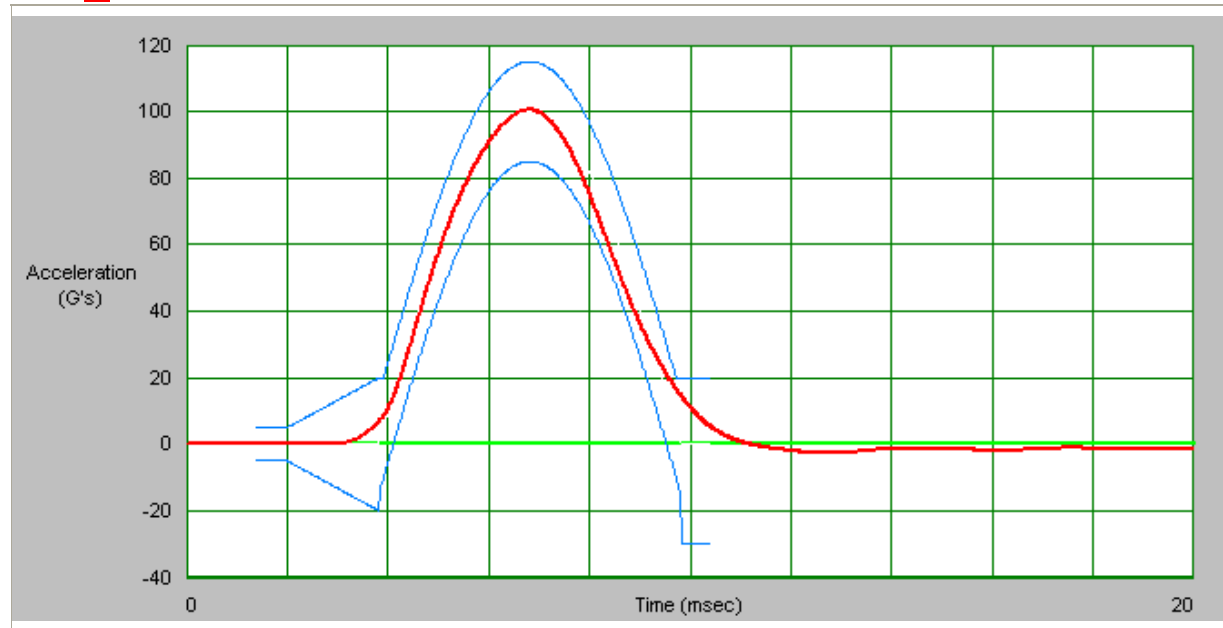
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Test Curve:

Acceleration vs Time

Channel Description:		G's	msec	In/S	Filter Hz	Max G's	Min G's
Ch1	Channel 1	100.50	6.12	147.83	422.30	100.50	-2.68



Axis -Z





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Test Seq. (d):

Test Item 2: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ20020	Mar. 18, 2011
Instantaneous circuit tester	NM11A	BTTEELSZ20016	Oct. 13, 2011

(2) Environmental Conditions:

Temperature: 18°C

Humidity: 47%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: PR101025117703-(009~011)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency (Hz)	PSD (g^2/Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56Grms

---Direction: Axis X, Y, Z

---Test duration: 2hours/axis

(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

---There shall be no low microsecond event detected greater than 1 microsecond.

Test Results: After the test, there was no evidence of physical damage to the tested samples and the low microsecond event detected was never greater than 1 microsecond. Other characteristics should be evaluated by the client.

Test Report

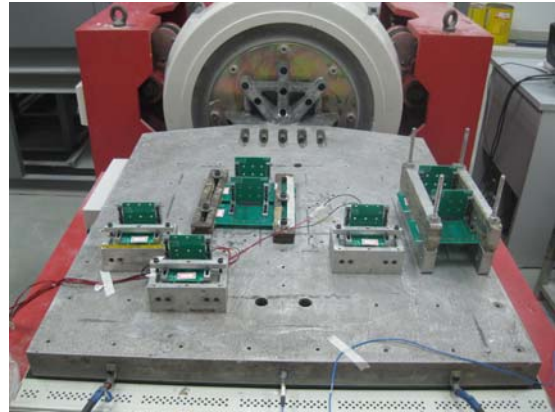
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Test Photos:



Axis X



Axis Y



Axis Z



monitor during the test

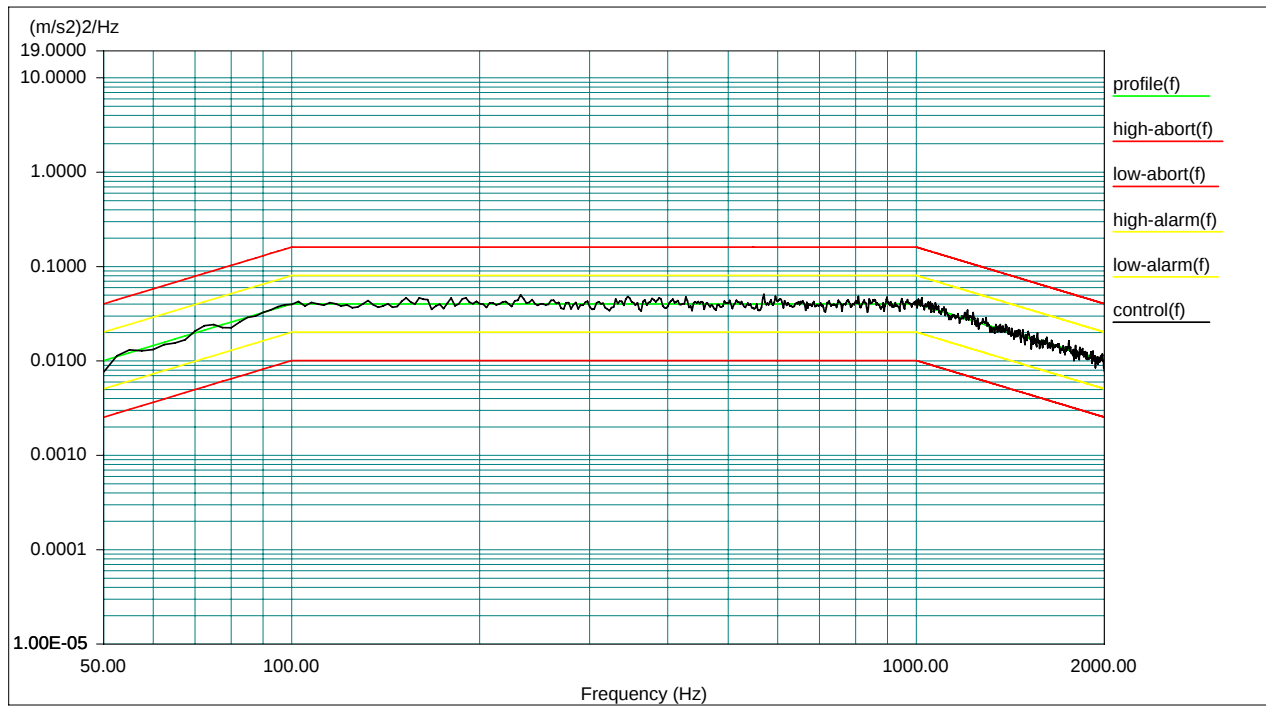


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Test Curve:



Level: 100 %

Control RMS: 7.573383 m/s² Full Level Elapsed Time: 02:00:00 Lines: 800 Frame Time: 0.400000
Seconds

Demand RMS: 7.564621 m/s² Remaining Time: 00:00:00 DOF: 154 dF: 2.500000 Hz

Data saved at 06:17:34 AM, Thursday, January 13, 2011

Report created at 06:17:35 AM, Thursday, January 13, 2011

Axis X



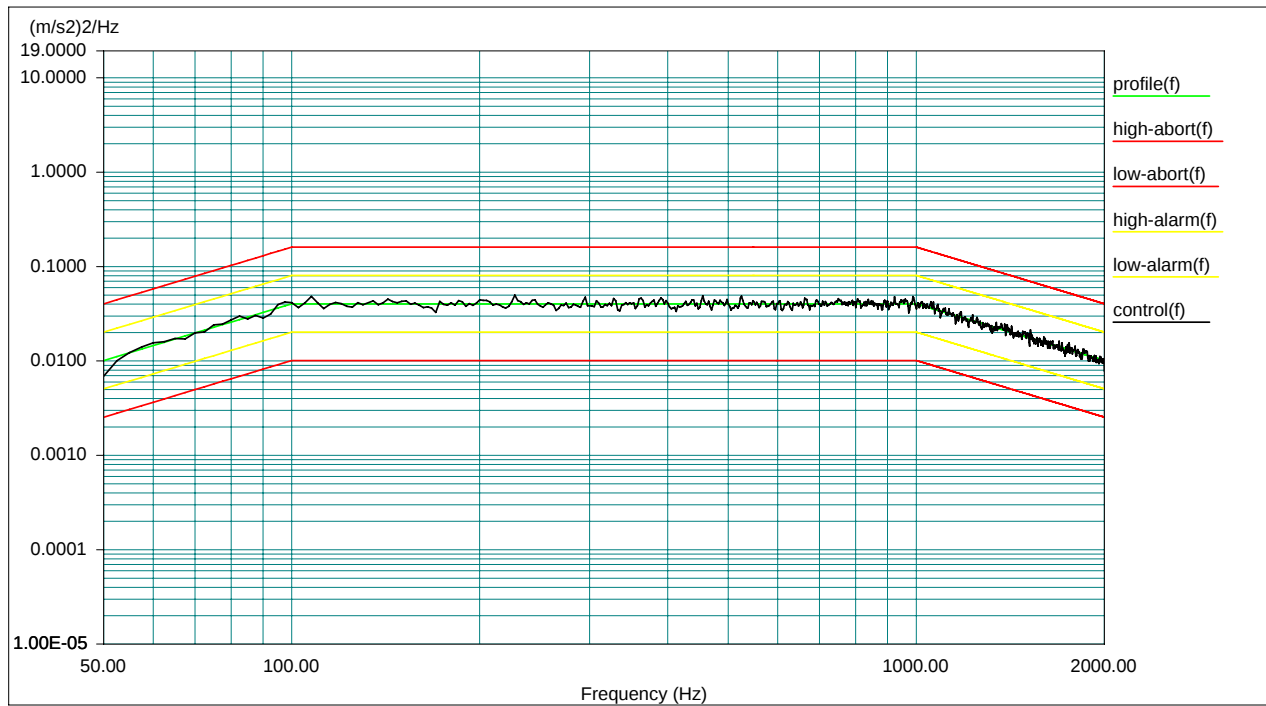


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Test Curve:



Level: 100 %

Control RMS: 7.573685 m/s² Full Level Elapsed Time: 02:00:00 Lines: 800 Frame Time: 0.400000
Seconds

Demand RMS: 7.564621 m/s² Remaining Time: 00:00:00 DOF: 154 dF: 2.500000 Hz

Data saved at 07:43:49 PM, Wednesday, January 12, 2011

Report created at 07:43:50 PM, Wednesday, January 12, 2011

Axis Y



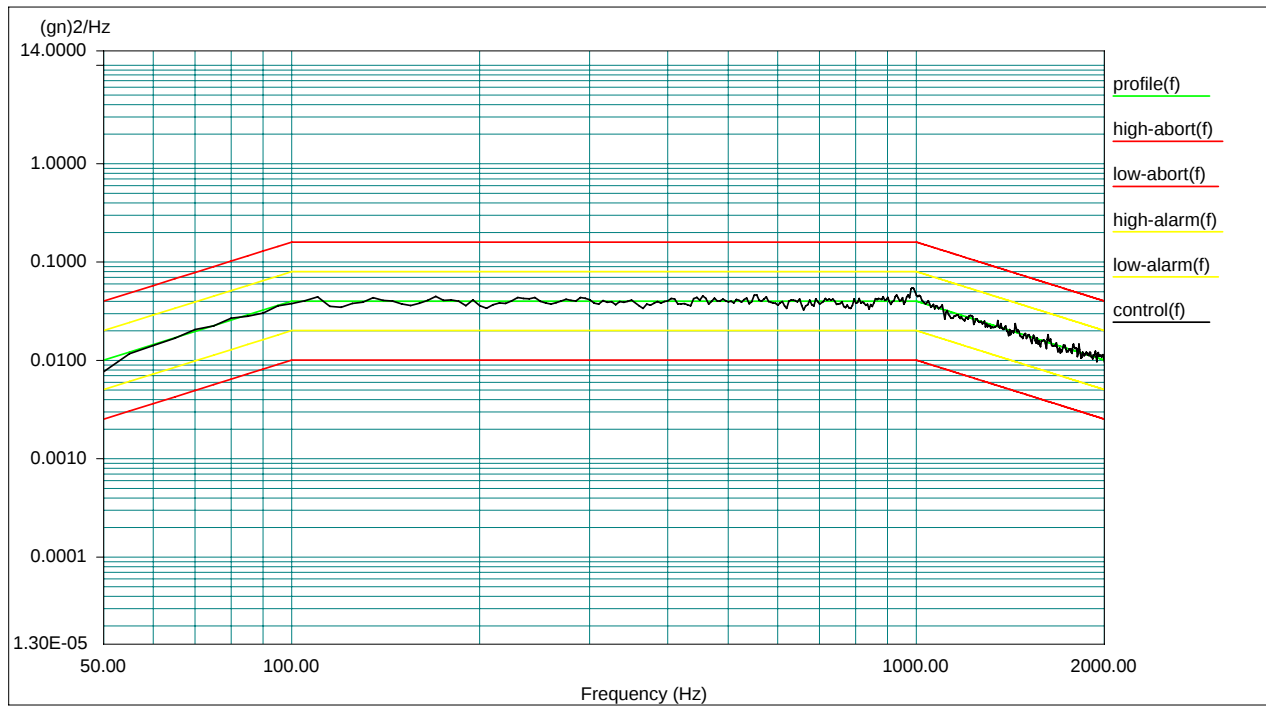


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Test Curve:



Level: 100 %

Control RMS: 7.799636 m/s² Full Level Elapsed Time: 02:00:00 Lines: 800 Frame Time: 0.400000
Seconds

Demand RMS: 7.564621 m/s² Remaining Time: 00:00:00 DOF: 154 dF: 2.500000 Hz

Data saved at 11:10:13 AM, Wednesday, January 12, 2011

Report created at 11:10:13 AM, Wednesday, January 12, 2011

Axis Z

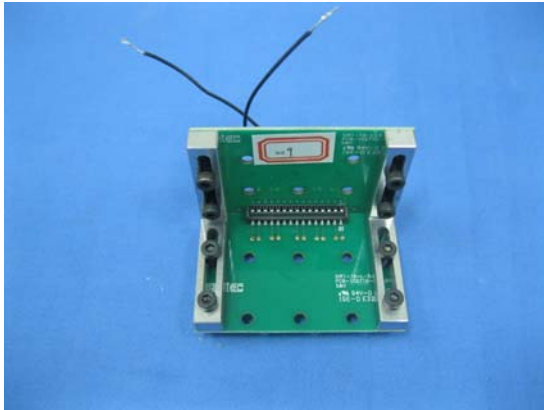


Test Report

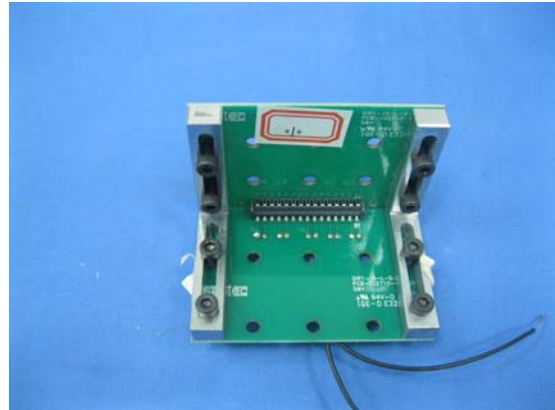
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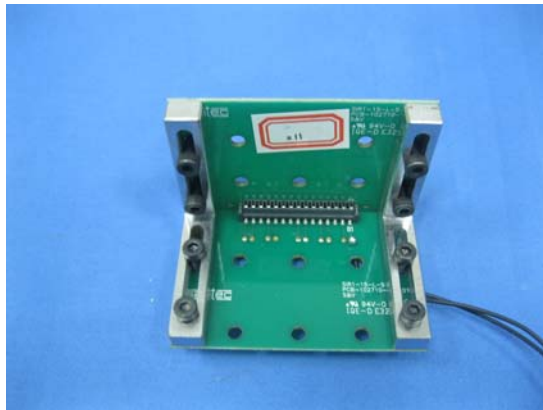
Sample Photos after Testing Seq. (d):



009



010



011

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Appendix: Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
001	pin1	13.60	13.96	0.36	11.73	-1.87
	pin2	14.06	14.30	0.24	11.95	-2.11
	pin3	14.05	14.32	0.27	11.86	-2.19
	pin4	14.34	14.50	0.16	12.05	-2.29
	pin5	14.78	15.08	0.30	12.63	-2.15
	pin6	14.16	14.51	0.35	12.10	-2.06
	pin7	13.90	14.36	0.46	11.98	-1.92
	pin8	14.00	14.35	0.35	11.86	-2.14
	pin9	14.27	14.58	0.31	12.07	-2.20
	pin10	14.12	14.56	0.44	12.06	-2.06
	pin11	14.36	14.89	0.53	12.43	-1.93
002	pin1	16.18	16.55	0.37	13.56	-2.62
	pin2	14.83	15.05	0.22	12.07	-2.76
	pin3	14.78	15.16	0.38	12.15	-2.63
	pin4	14.89	15.23	0.34	12.70	-2.19
	pin5	14.65	15.48	0.83	12.53	-2.12
	pin6	14.70	15.08	0.38	12.50	-2.20
	pin7	14.79	15.20	0.41	12.86	-1.93
	pin8	15.02	15.81	0.79	12.48	-2.54
	pin9	14.88	15.19	0.31	12.58	-2.30
	pin10	14.51	15.13	0.62	12.62	-1.89
	pin11	14.75	15.11	0.36	12.53	-2.22
	pin1	16.18	16.55	0.37	13.56	-2.62
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Test Report

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Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
003	pin1	14.52	15.18	0.66	17.65	3.13
	pin2	14.19	15.40	1.21	15.95	1.76
	pin3	14.16	15.10	0.94	14.35	0.19
	pin4	14.44	15.30	0.86	14.39	-0.05
	pin5	14.71	16.00	1.29	14.28	-0.43
	pin6	14.57	15.07	0.50	14.26	-0.31
	pin7	14.26	15.24	0.98	14.03	-0.23
	pin8	14.42	15.37	0.95	14.23	-0.19
	pin9	14.68	15.17	0.49	15.27	0.59
	pin10	14.79	15.39	0.60	14.07	-0.72
	pin11	14.43	15.11	0.68	14.62	0.19
004	pin1	13.73	14.59	0.86	11.75	-1.98
	pin2	13.93	14.98	1.05	12.11	-1.82
	pin3	14.00	14.49	0.49	11.80	-2.20
	pin4	14.12	14.73	0.61	11.96	-2.16
	pin5	13.96	14.59	0.63	11.87	-2.09
	pin6	14.01	14.55	0.54	11.75	-2.26
	pin7	14.18	14.86	0.68	11.92	-2.26
	pin8	14.51	15.02	0.51	12.19	-2.32
	pin9	15.42	17.04	1.62	13.36	-2.06
	pin10	14.26	14.96	0.70	11.94	-2.32
	pin11	14.79	15.64	0.85	12.41	-2.38
	pin1	13.73	14.59	0.86	11.75	-1.98
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

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Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
005	pin1	14.57	14.93	0.36	11.23	-3.34
	pin2	14.35	15.59	1.24	11.66	-2.69
	pin3	14.00	14.80	0.80	11.98	-2.02
	pin4	14.91	15.65	0.74	11.81	-3.10
	pin5	14.30	14.64	0.34	11.91	-2.39
	pin6	14.53	15.17	0.64	11.94	-2.59
	pin7	14.45	15.28	0.83	11.58	-2.87
	pin8	14.76	15.44	0.68	11.67	-3.09
	pin9	14.75	15.69	0.94	11.55	-3.20
	pin10	14.07	14.98	0.91	12.29	-1.78
	pin11	14.31	15.24	0.93	12.37	-1.94
006	pin1	13.94	14.91	0.97	13.29	-0.65
	pin2	14.03	14.62	0.59	13.68	-0.35
	pin3	14.30	15.07	0.77	14.14	-0.16
	pin4	14.27	15.00	0.73	18.28	4.01
	pin5	14.56	15.32	0.76	14.95	0.39
	pin6	14.18	14.79	0.61	14.34	0.16
	pin7	14.25	14.81	0.56	13.12	-1.13
	pin8	14.69	15.37	0.68	14.75	0.06
	pin9	14.40	15.17	0.77	15.47	1.07
	pin10	14.63	15.42	0.79	18.45	3.82
	pin11	14.70	16.10	1.40	15.56	0.86
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

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Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
007	pin1	13.46	13.83	0.37	11.35	-2.11
	pin2	13.94	14.43	0.49	11.82	-2.12
	pin3	14.23	14.43	0.20	11.89	-2.34
	pin4	14.09	14.42	0.33	11.99	-2.10
	pin5	14.57	14.75	0.18	12.15	-2.42
	pin6	14.38	14.87	0.49	12.22	-2.16
	pin7	14.22	14.61	0.39	12.22	-2.00
	pin8	14.05	14.56	0.51	11.92	-2.13
	pin9	14.17	14.57	0.40	12.02	-2.15
	pin10	13.98	14.52	0.54	12.23	-1.75
	pin11	16.22	16.81	0.59	13.97	-2.25
008	pin1	13.77	14.27	0.50	11.64	2.13
	pin2	14.53	14.70	0.17	11.82	2.71
	pin3	14.60	14.91	0.31	11.68	2.92
	pin4	14.82	14.98	0.16	11.71	3.11
	pin5	13.92	14.23	0.31	11.55	2.37
	pin6	14.49	14.60	0.11	11.72	2.77
	pin7	14.26	14.98	0.72	11.67	2.59
	pin8	14.18	14.98	0.80	11.98	2.20
	pin9	13.89	14.35	0.46	11.78	2.11
	pin10	13.83	14.26	0.43	11.81	2.02
	pin11	13.84	14.22	0.38	12.09	1.75
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

*** End of report ***

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